



## 54ACTQ/74ACTQ827 Quiet Series 10-Bit Buffer/Line Driver with TRI-STATE® Outputs

### General Description

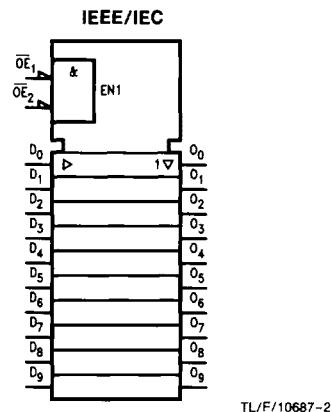
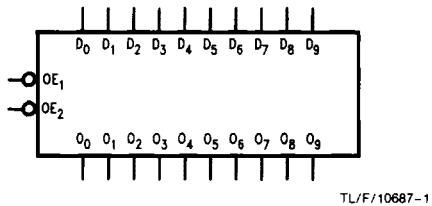
The 'ACTQ827 10-bit bus buffer provides high performance bus interface buffering for wide data/address paths or buses carrying parity. The 10-bit buffers have NOR output enables for maximum control flexibility. The 'ACTQ827 utilizes NSC Quiet Series technology to guarantee quiet output switching and improved dynamic threshold performance. FACT Quiet Series™ feature GTOTM output control and undershoot corrector in addition to a split ground bus for superior performance.

### Features

- Guaranteed simultaneous switching noise level and dynamic threshold performance
- Guaranteed pin-to-pin skew AC performance
- Inputs and outputs on opposite sides of package allow easy interface with microprocessors
- Improved latch-up immunity
- Outputs source/sink 24 mA
- Functionally and pin-compatible to AMD's AM29827
- 'ACTQ827 has TTL-compatible inputs
- 4 kV minimum ESD immunity
- Standard Military Drawing (SMD)  
— 'ACTQ827: 5962-92199

**Ordering Code:** See Section 8

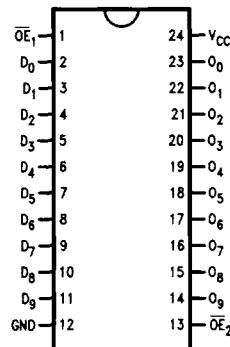
### Logic Symbols



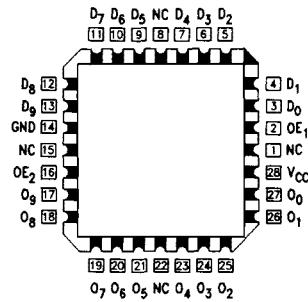
Pin Names	Description
OE <sub>1</sub> , OE <sub>2</sub>	Output Enable
D <sub>0</sub> -D <sub>9</sub>	Data Inputs
O <sub>0</sub> -O <sub>9</sub>	Data Outputs

### Connection Diagrams

Pin Assignment  
for DIP, Flatpak and SOIC



Pin Assignment  
for LCC



## Functional Description

The 'ACTQ827 line driver is designed to be employed as memory address driver, clock driver and bus-oriented transmitter/receiver. The devices have TRI-STATE outputs controlled by the Output Enable ( $\overline{OE}$ ) pins. When the  $\overline{OE}$  is LOW, the device is transparent. When  $\overline{OE}$  is HIGH, the device is in TRI-STATE mode.

Function Table

Inputs	Outputs		Function	
	$\overline{OE}$	$D_n$	$O_n$	
L	H		H	Transparent
L	L		L	Transparent
H	X		Z	High Z

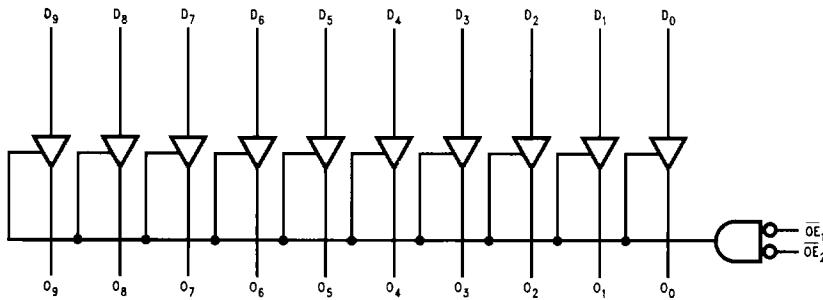
H = HIGH Voltage Level

L = LOW Voltage Level

Z = HIGH Impedance

X = Immaterial

## Logic Diagram



TL/F/10687-5

Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

## Absolute Maximum Rating (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Supply Voltage ( $V_{CC}$ )	$-0.5V$ to $+7.0V$
DC Input Diode Current ( $I_{IK}$ ) $V_I = -0.5V$	$-20\text{ mA}$
$V_I = V_{CC} + 0.5V$	$+20\text{ mA}$
DC Input Voltage ( $V_I$ )	$-0.5V$ to $V_{CC} + 0.5V$
DC Output Diode Current ( $I_{OK}$ ) $V_O = -0.5V$	$-20\text{ mA}$
$V_O = V_{CC} + 0.5V$	$+20\text{ mA}$
DC Output Voltage ( $V_O$ )	$-0.5V$ to $V_{CC} + 0.5V$
DC Output Source or Sink Current ( $I_O$ )	$\pm 50\text{ mA}$
DC $V_{CC}$ or Ground Current per Output Pin ( $I_{CC}$ or $I_{GND}$ )	$\pm 50\text{ mA}$
Storage Temperature ( $T_{STG}$ )	$-65^\circ C$ to $+150^\circ C$
DC Latch-Up Source or Sink Current	$\pm 300\text{ mA}$
Junction Temperature ( $T_J$ ) CDIP PDIP	$175^\circ C$ $140^\circ C$

**Note 1:** Absolute maximum ratings are those values beyond which damage to the device may occur. The databook specifications should be met, without exception, to ensure that the system design is reliable over its power supply, temperature, and output/input loading variables. National does not recommend operation of FACT™ circuits outside databook specifications.

## Recommended Operating Conditions

Supply Voltage ( $V_{CC}$ ) 'ACTQ	$4.5V$ to $5.5V$
Input Voltage ( $V_I$ )	$0V$ to $V_{CC}$
Output Voltage ( $V_O$ )	$0V$ to $V_{CC}$
Operating Temperature ( $T_A$ ) 74ACTQ 54ACTQ	$-40^\circ C$ to $+85^\circ C$ $-55^\circ C$ to $+125^\circ C$

### Minimum Input Edge Rate $\Delta V/\Delta t$

'ACTQ Devices

$V_{IN}$  from  $0.8V$  to  $2.0V$

$V_{CC} @ 4.5V, 5.5V$

$125\text{ mV/ns}$

**Note:** All commercial packaging is not recommended for applications requiring greater than 2000 temperature cycles from  $-40^\circ C$  to  $+125^\circ C$ .

## DC Electrical Characteristics for 'ACTQ Family Devices

Symbol	Parameter	$V_{CC}$ (V)	74ACTQ		54ACTQ	74ACTQ	Units	Conditions
			$T_A = +25^\circ C$		$T_A =$ $-55^\circ C$ to $+125^\circ C$	$T_A =$ $-40^\circ C$ to $+85^\circ C$		
			Typ	Guaranteed Limits				
$V_{IH}$	Minimum High Level Input Voltage	4.5 5.5	1.5 1.5	2.0 2.0	2.0 2.0	2.0 2.0	V	$V_{OUT} = 0.1V$ or $V_{CC} - 0.1V$
$V_{IL}$	Maximum Low Level Input Voltage	4.5 5.5	1.5 1.5	0.8 0.8	0.8 0.8	0.8 0.8	V	$V_{OUT} = 0.1V$ or $V_{CC} - 0.1V$
$V_{OH}$	Minimum High Level Output Voltage	4.5 5.5	4.49 5.49	4.4 5.4	4.4 5.4	4.4 5.4	V	$I_{OUT} = -50\text{ }\mu A$
		4.5 5.5		3.86 4.86	3.70 4.70	3.76 4.76	V	* $V_{IN} = V_{IL}$ or $V_{IH}$ $I_{OH} = -24\text{ mA}$
$V_{OL}$	Maximum Low Level Output Voltage	4.5 5.5	0.001 0.001	0.1 0.1	0.1 0.1	0.1 0.1	V	$I_{OUT} = 50\text{ }\mu A$
		4.5 5.5		0.36 0.36	0.50 0.50	0.44 0.44	V	* $V_{IN} = V_{IL}$ or $V_{IH}$ $I_{OL} = 24\text{ mA}$
$I_{IN}$	Maximum Input Leakage Current	5.5		$\pm 0.1$	$\pm 1.0$	$\pm 1.0$	$\mu A$	$V_I = V_{CC}, GND$
$I_{OZ}$	Maximum TRI-STATE® Current	5.5		$\pm 0.5$	$\pm 10.0$	$\pm 5.0$	$\mu A$	$V_I = V_{IL}, V_{IH}$ $V_O = V_{CC}, GND$
$I_{CCT}$	Maximum $I_{CC}/$ Input	5.5	0.6		1.6	1.5	mA	$V_I = V_{CC} - 2.1V$

\*All outputs loaded; thresholds on input associated with output under test.

## DC Electrical Characteristics for 'ACTQ Family Devices (Continued)

Symbol	Parameter	V <sub>CC</sub> (V)	74ACTQ		54ACTQ	74ACTQ	Units	Conditions
			T <sub>A</sub> = +25°C		T <sub>A</sub> = -55°C to +125°C	T <sub>A</sub> = -40°C to +85°C		
			Typ	Guaranteed Limits				
I <sub>OLD</sub>	†Minimum Dynamic Output Current	5.5			50	75	mA	V <sub>OLD</sub> = 1.65V Max
I <sub>OHD</sub>		5.5			-50	-75	mA	V <sub>OHD</sub> = 3.85V Min
I <sub>CC</sub>	Maximum Quiescent Supply Current	5.5		8.0	160.0	80.0	µA	V <sub>IN</sub> = V <sub>CC</sub> or GND (Note 1)
V <sub>O LP</sub>	Quiet Output Maximum Dynamic V <sub>OL</sub>	5.0	1.1	1.6V			V	Figures 2-12, 13 (Notes 2, 3)
V <sub>O LV</sub>	Quiet Output Minimum Dynamic V <sub>OL</sub>	5.0	-0.6	-1.3			V	Figures 2-12, 13 (Notes 2, 3)
V <sub>I HD</sub>	Minimum High Level Dynamic Input Voltage	5.0	1.9	2.0			V	(Notes 2, 4)
V <sub>I LD</sub>	Maximum Low Level Dynamic Input Voltage	5.0	1.2	0.8			V	(Notes 2, 4)

†Maximum test duration 2.0 ms, one output loaded at a time.

Note 1: I<sub>CC</sub> for 54ACTQ @ 25°C is identical to 74ACTQ @ 25°C.

Note 2: Plastic DIP package.

Note 3: Max number of outputs defined as (n). Data inputs are driven 0V to 3V. One output @ GND.

Note 4: Max number of data inputs (n-1) inputs switching 0V to 3V ('ACTQ). Input-under-test switching: 3V to threshold (V<sub>ILD</sub>), 0V to threshold (V<sub>IHD</sub>), f = 1 MHz.

## AC Electrical Characteristics: See Section 2 for Waveforms

Symbol	Parameter	V <sub>CC</sub> * (V)	74ACTQ			54ACTQ	74ACTQ	Units	Fig. No.
			T <sub>A</sub> = +25°C C <sub>L</sub> = 50 pF			T <sub>A</sub> = -55°C to +125°C C <sub>L</sub> = 50 pF	T <sub>A</sub> = -40°C to +85°C C <sub>L</sub> = 50 pF		
			Min	Typ	Max	Min	Max		
t <sub>PHL</sub> , t <sub>PLH</sub>	Propagation Delay Data to Output	5.0	2.5	5.6	8.0	2.0	9.5	2.5	9.0 ns 2-3, 4
t <sub>PZL</sub> , t <sub>PZH</sub>	Output Enable Time	5.0	3.0	7.1	10.0	2.0	12.5	3.0	11.0 ns 2-5, 6
t <sub>PHZ</sub> , t <sub>PLZ</sub>	Output Disable Time	5.0	1.0	5.8	8.0	1.0	9.0	1.0	8.5 ns 2-5, 6
t <sub>O SHL</sub> , t <sub>O SLH</sub>	Output to Output Skew** Data to Output	5.0		0.5	1.5			1.5	ns

\*Voltage Range 5.0 is 5.0V ± 0.5V.

\*\*Skew is defined as the absolute value of the difference between the actual propagation delay for any two outputs within the same packaged device. The specification applies to any outputs switching in the same direction, either HIGH to LOW (t<sub>O SHL</sub>) or LOW to HIGH (t<sub>O SLH</sub>). Parameter guaranteed by design. Not tested.

## Capacitance

Symbol	Parameter	Typ	Units	Conditions
C <sub>IN</sub>	Input Capacitance	4.5	pF	V <sub>CC</sub> = OPEN
C <sub>PD</sub>	Power Dissipation Capacitance	82	pF	V <sub>CC</sub> = 5.0V